

FIG. 1 is a schematic diagram of a system 10 for testing a device 12. The system 10 includes a power supply 20, an AC source 21, a DC source 28, and a control unit 30. The device 12 is connected to the power supply 20 and the AC source 21. The control unit 30 is connected to the DC source 28 and the device 12. The system 10 is configured to provide a controlled environment for testing the device 12.

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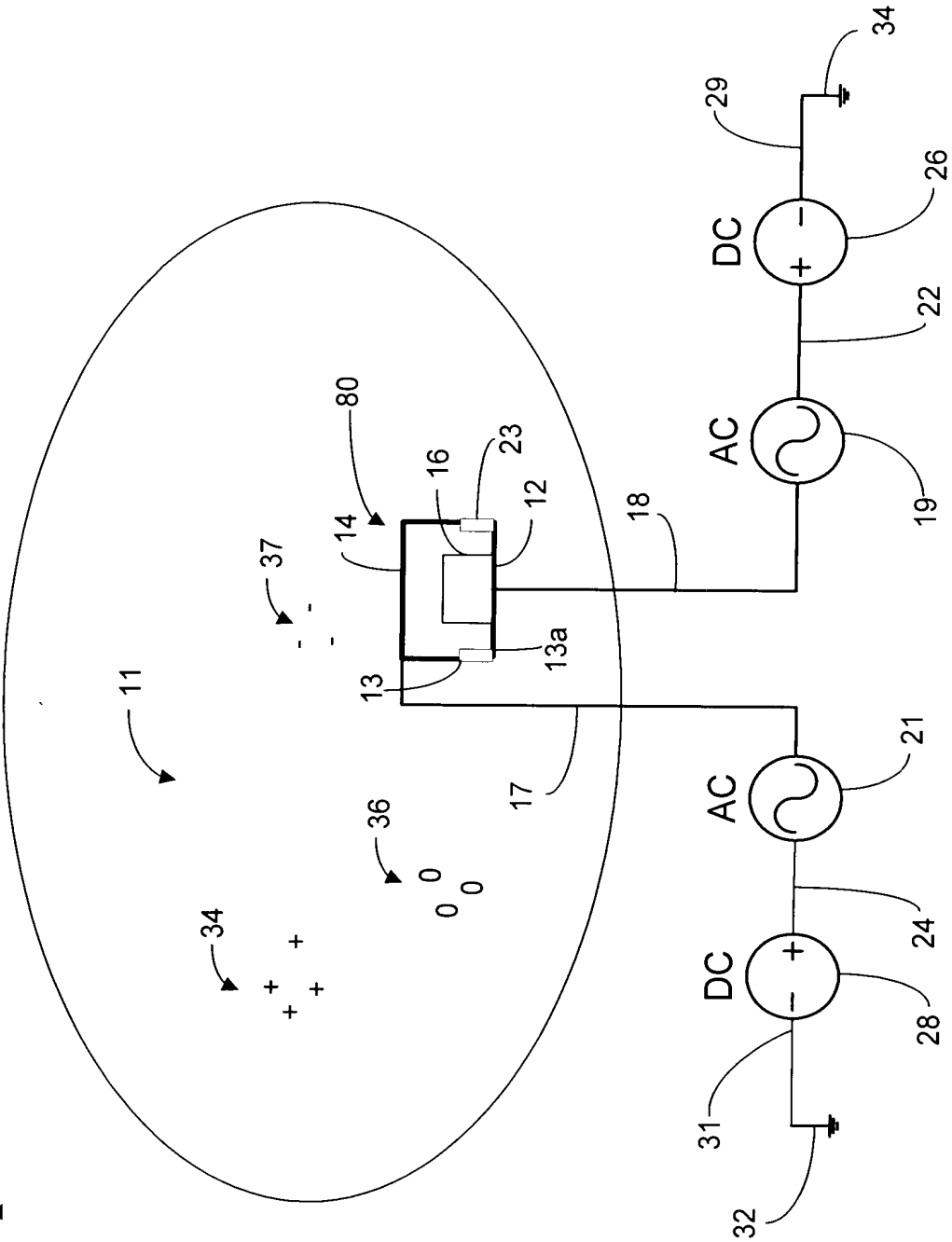


Fig. 1

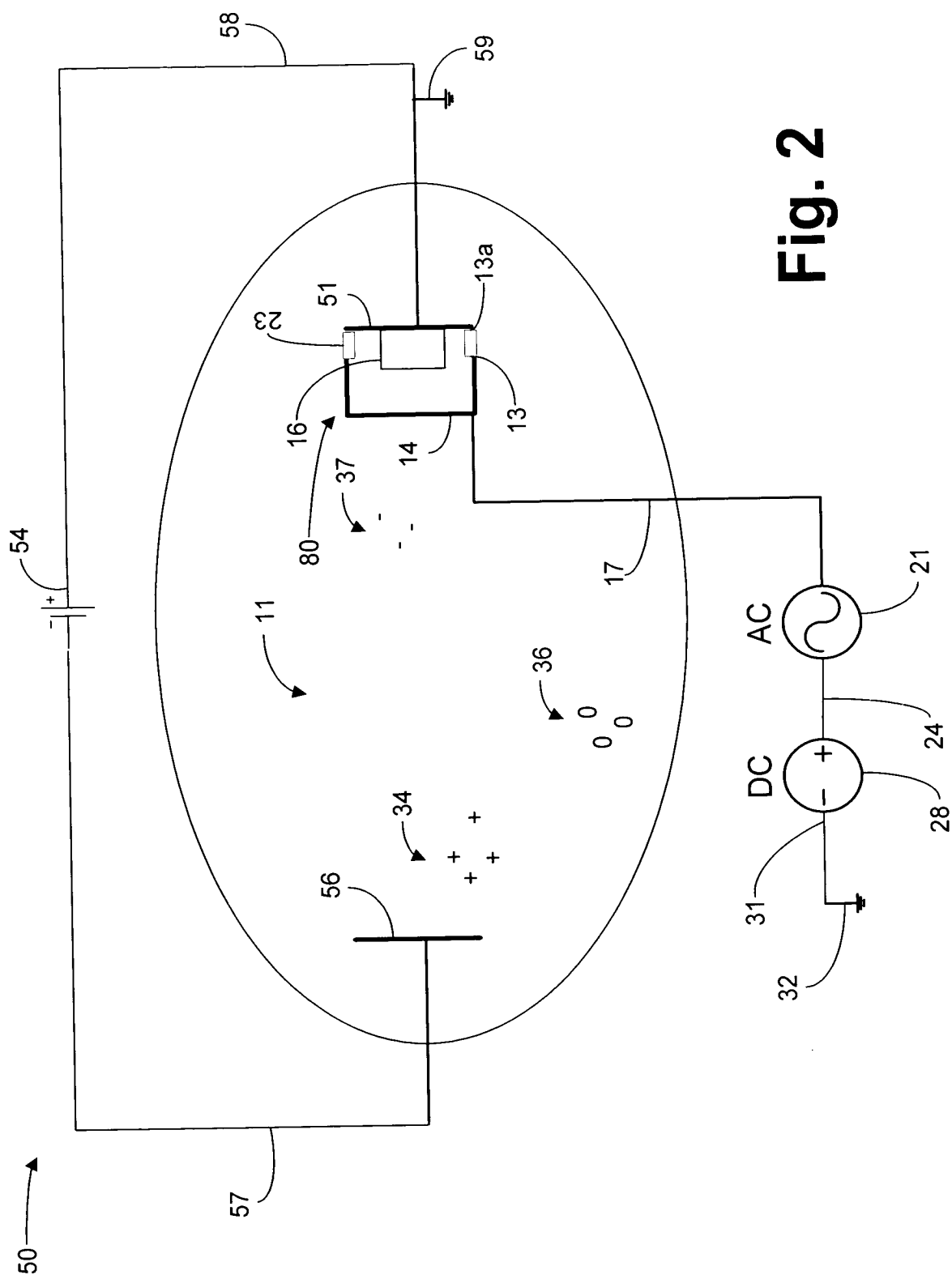
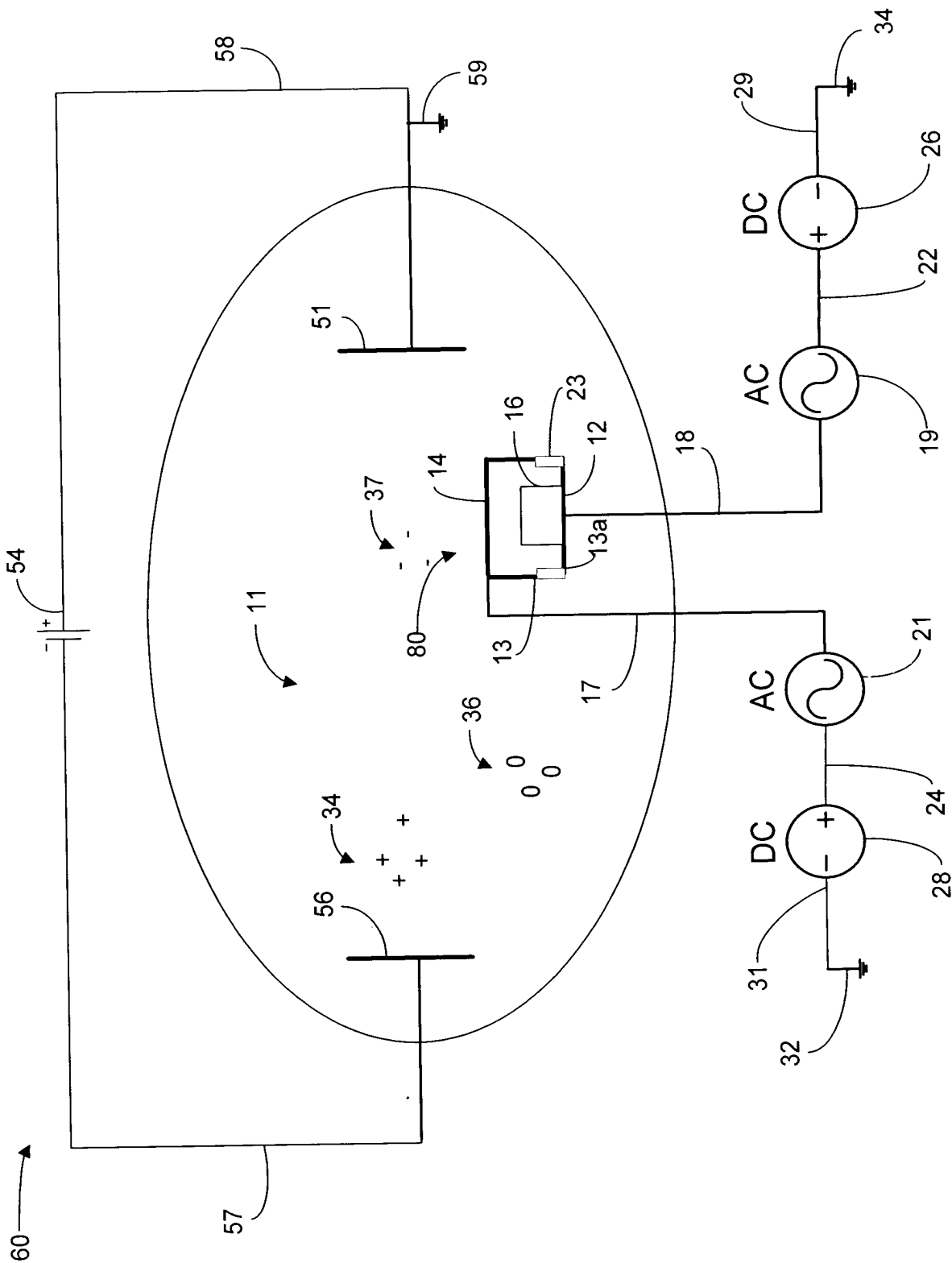
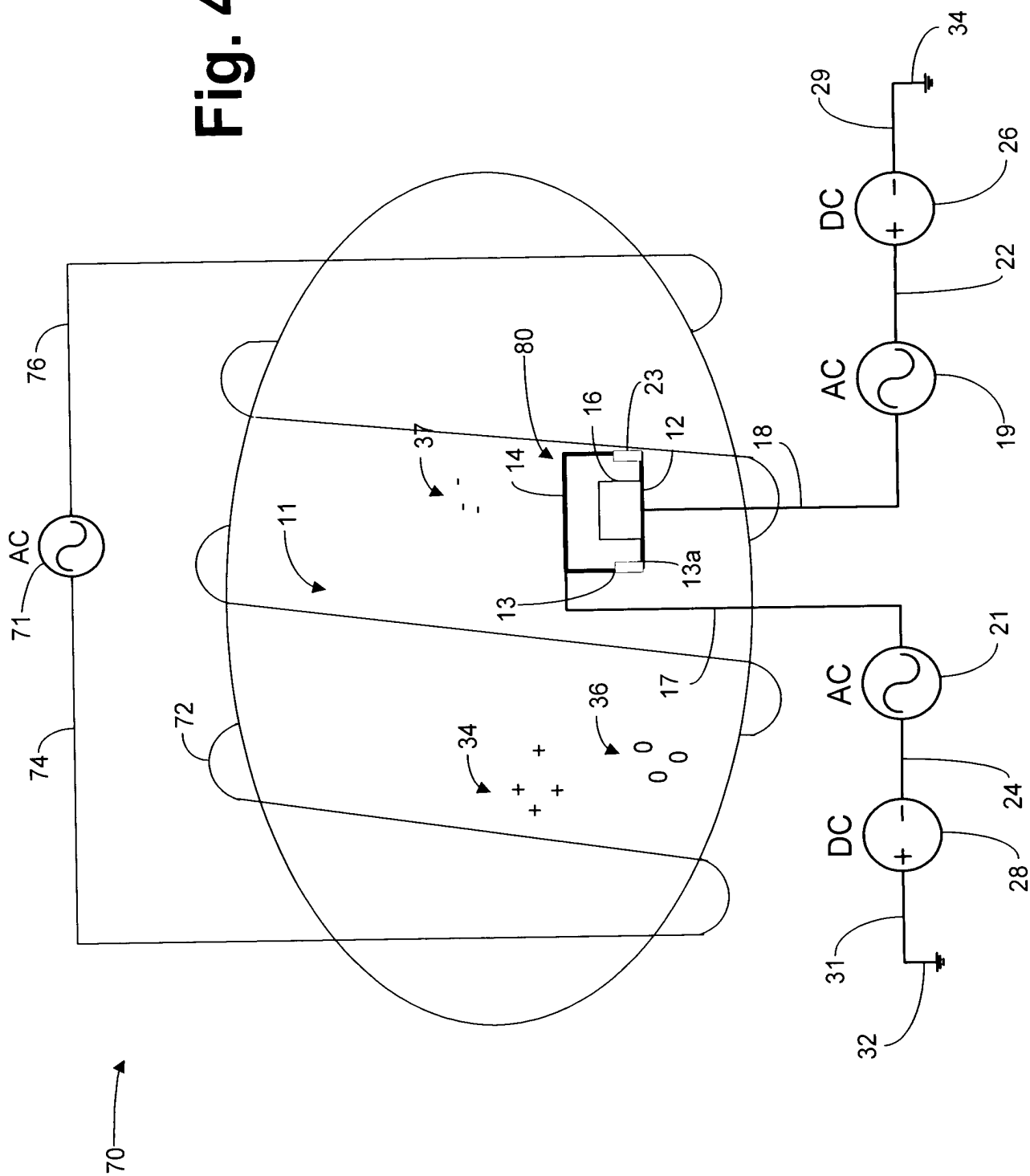


FIG. 3 is a schematic diagram of a system for testing a device under test (DUT) 11. The system includes a power supply 54, a DC voltage source 28, an AC voltage source 21, a DC voltage source 26, an AC voltage source 19, a DC voltage source 34, and a DC voltage source 32. The DUT 11 is connected to the power supply 54 and the DC voltage source 28. The DC voltage source 28 is connected to the AC voltage source 21. The AC voltage source 21 is connected to the DC voltage source 26. The DC voltage source 26 is connected to the AC voltage source 19. The AC voltage source 19 is connected to the DC voltage source 34. The DC voltage source 34 is connected to the DC voltage source 32.



**Fig. 3**

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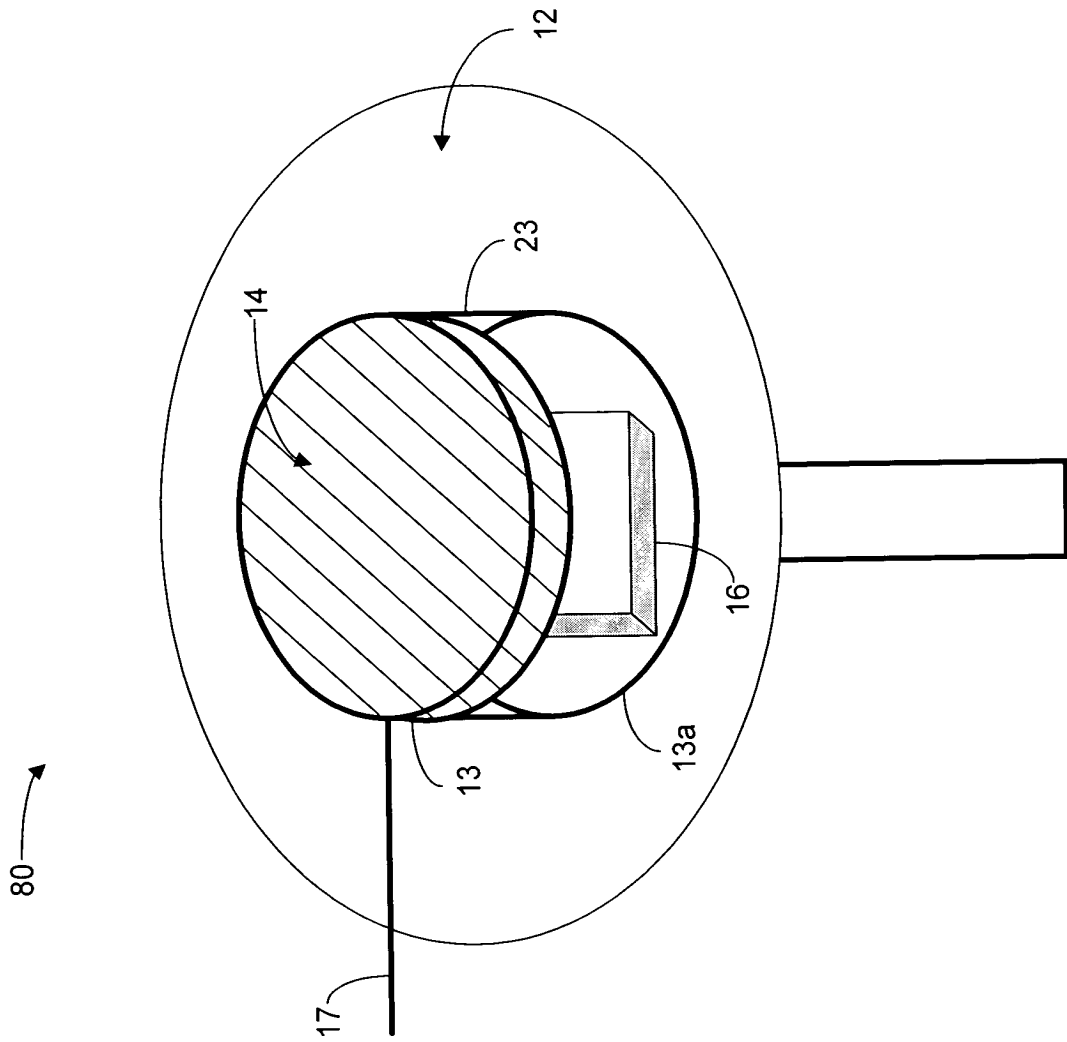


Fig. 5a

FIG. 5 is a perspective view of the device 80 in a closed position. The device 80 includes a housing 12, a lid 14, a base 16, and a handle 17. The lid 14 is hinged to the housing 12 and is shown in a closed position. The base 16 is attached to the housing 12 and the handle 17 is attached to the base 16. The device 80 is shown in a perspective view.

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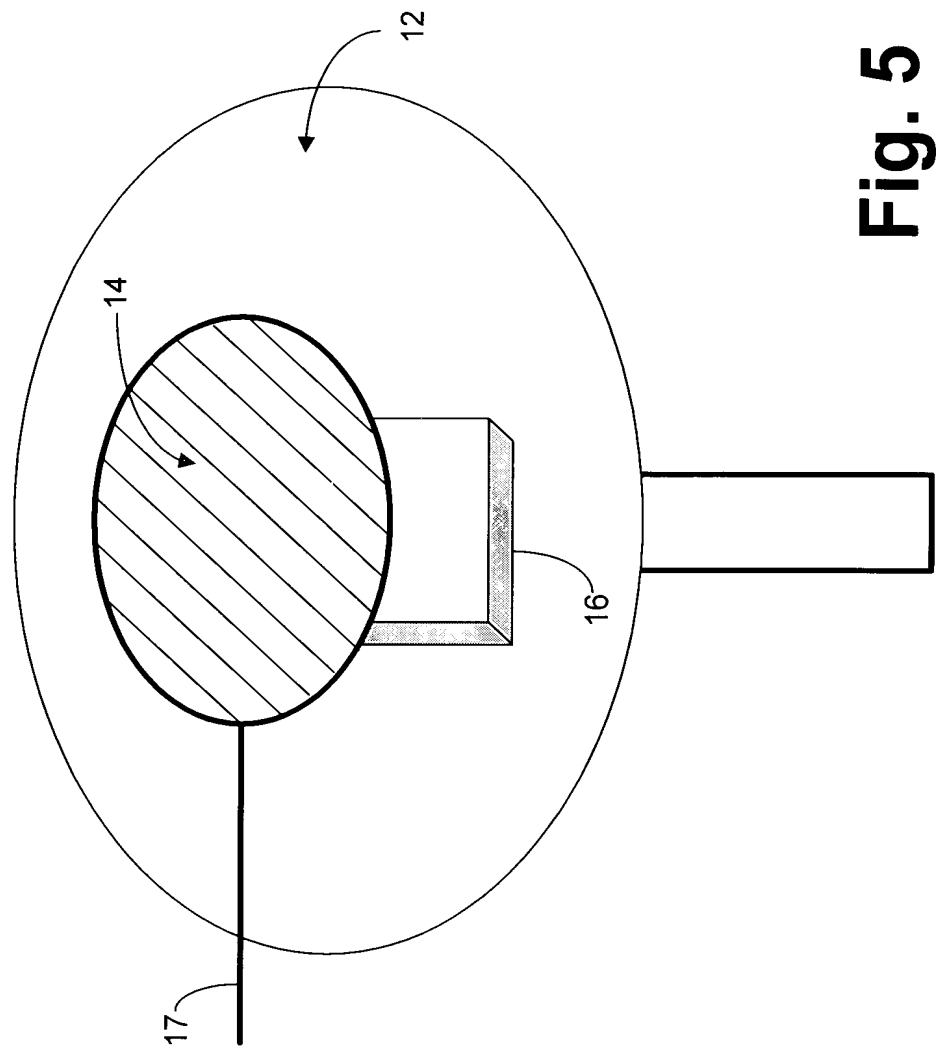


Fig. 5